

X-ray Compton Tomography

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Abstract

The potentials of incoherent X-ray scattering (Compton) tomography are investigated. Imaging materials of very different density or atomic number at once is a perpetual challenge for X-ray tomography or radiography, in general. In a basic laboratory set-up for simultaneous perpendicular Compton scattering and direct beam attenuation tomographic scans are conducted by single channel photon counting. This results in asymmetric distortions of the projection profiles of the scattering CT-data set. In a first approach corrections of Compton scattering data by taking advantage of rotational symmetry yield tomograms without major geometric artefacts. A cylindrical sample composed of PE, PA, PVC, glass and wood demonstrates similar Compton contrast for all the substances, while the conventional absorption tomogram only reveals the two high order materials. Comparison to neutron tomography reveals astonishing similarities except for the glass component (without hydrogen). Therefore, Compton CT bears the potential to replace neutron tomography, which requires much more efforts.

Keywords: X-ray Compton scattering, Computed tomography, Neutron tomography

1. Introduction

The rapidly growing field of applications in non-destructive testing by X-ray radiographic and tomographic techniques comes along with increased requirements for measurement speed and spatial resolution as well as for structural complexity and highly different materials interaction. In recent decades very different approaches have been developed to satisfy the demands. Within the course of events the essential physical interactions with matter has been extended from solely measuring attenuation by absorption towards application of coherent and incoherent scattering [1, 2], refraction [3-9], interferometry [10, 11] and fluorescence for the purpose of imaging.

The various techniques have served as well for creating tomographic projection data sets in order to reconstruct three-dimensional views of material properties such as density, porosity, crystallites [12-14] or element distribution by fluorescent tomography [15, 16], specific surface [17-19], and interface orientation [19, 20].

Referring to Compton imaging previous techniques have preferably applied “triangulation” of the primary and scattered beams [1, 2]. Relatively low attention has been paid to Compton tomography although it provides the potential of contrasting materials of a broad range of atomic numbers simultaneously [21-29].

2. Compton scattering – basics

Considering the limitations of X-ray transmission through materials of considerably different atomic numbers by extremely different attenuation the application of Compton scattering [30] has the advantage of similar contrast, when test samples are composed of high and low atomic weight phases. A comparison of absorption and Compton interaction is demonstrated by the cross-sections in dependence of atomic numbers at 17.5 keV photon energy in Fig. 1, giving the individually extremely different “true” (photoelectric) absorption at the left and the smaller differences of incoherent scattering between elements at the right.

The transmission intensity I of materials of density ρ and chord length d by X-rays of primary intensity I_o is controlled by the mass attenuation coefficient μ according to

$$I = I_o \exp[-\rho \mu d]. \quad (1)$$

All the energy dependent interactions of photoelectric effect τ , coherent σ_{coh} , incoherent σ_{inc} and pair production π add up to μ :

$$\mu(E) = \tau(E) + \sigma_{coh}(E) + \sigma_{inc}(E) + \pi(E) \quad (2)$$

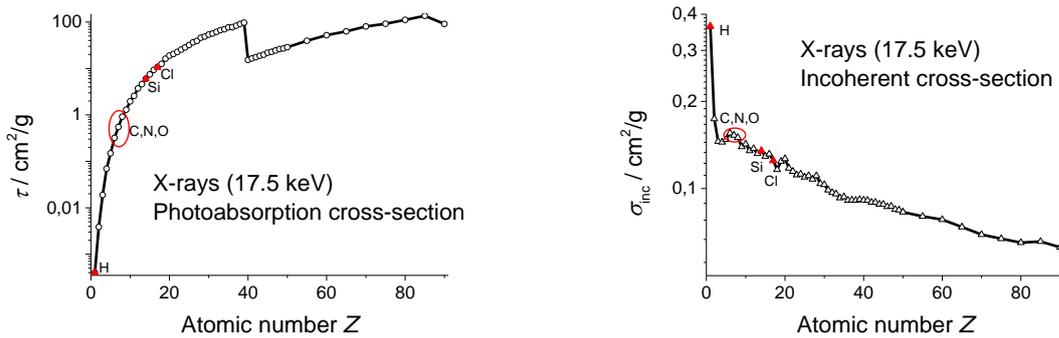


Fig. 1: Absorption and Compton X-ray interaction with matter by cross-sections over atomic numbers at 17.5 keV photon energy; left: extremely different “true” (photoelectric) absorption; right: relatively similar inelastic scattering (data from [31]).

The basic principles of Compton scattering of photons at electrons (incoherent scattering) are demonstrated by Fig.2. The angular dependence of the scattered photon’s wavelength or energy shift is given by

$$\lambda' - \lambda = \frac{h}{m_e c} (1 - \cos \theta) \quad \text{or} \quad E' = \frac{E}{1 + \varepsilon(1 - \cos \theta)}, \quad (3)$$

with $\varepsilon = E/m_e c^2$, i.e. the multiple (fraction) of an electron’s rest energy, given by the electron mass m_e and the speed of light c .

According to (3), the „maximum wavelength shift“ occurs at scattering angle $\theta = \pi$. It is limited by the Compton wavelength 2.42 pm and independent of the incident photon energy.

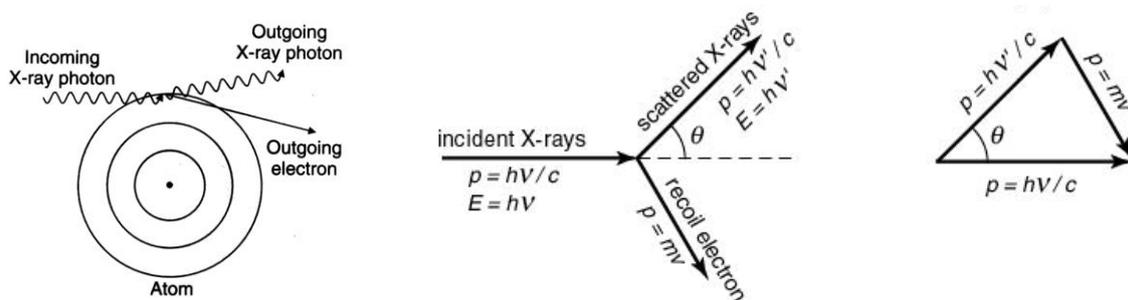


Fig. 2: Basic interactions of photons and electrons in case of incoherent scattering and conservation of energy and momentum [32, 33].

A comparison of the angular distribution of Compton and Rayleigh scattering is given by Fig. 3, which provides the angular scattering distribution by cross sections of 40 keV X-rays at Al. Fig 3 shows at left the incoherent free electron (Klein Nishina, [34]) and Al Compton

scattering considering scattering electron binding effects by correcting the Klein-Nishina cross section by the nonrelativistic Hartree-Fock incoherent scattering functions and at right the coherent free electron (Thomson) and Al scattering cross sections at bound electron by correcting the Thompson cross section by relativistic Hartree-Fock atomic form factor [35, 36]. For detection purposes the essential property of incoherent scattering is given by the rather isotropic scattering outside the narrow coherent forward sector.

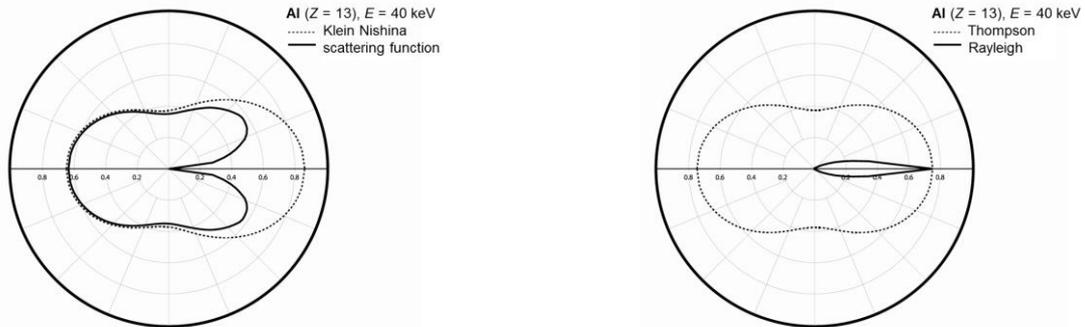


Fig. 3: Comparison of angular distribution of Compton and Rayleigh scattering of Al at 40 keV; left: incoherent free electron (Klein Nishina) and Al Compton scattering cross sections; right: coherent free electron (Thomson) and Al scattering cross sections [35].

3. Twin X-ray interaction tomography

A twin interaction laboratory set-up for (first generation) parallel beam 2D attenuation tomography and Compton scattering tomography is employed for test measurements on low density non-metallic materials of atomic numbers up to 17. The experimental principles are presented by Fig. 4. A 40 μm pencil beam from a Mo X-ray fine structure tube is used for vertical line scans of the sample by 17.5 keV radiation. Without further collimation the attenuation detector measures the primary beam including minor contributions of scattering (both, coherent and incoherent). The scattering detector is arranged perpendicular to the primary beam direction. Without secondary collimation it detects the incoherent scattering at approximately $\theta = 90^\circ$ simultaneously. Both intensities at each projection angle out of a 360° rotation are registered by single photon counting scintillation detectors. The line profiles of both interactions are stored and arranged in separate sinograms for the image reconstruction of the scanned sample layer.

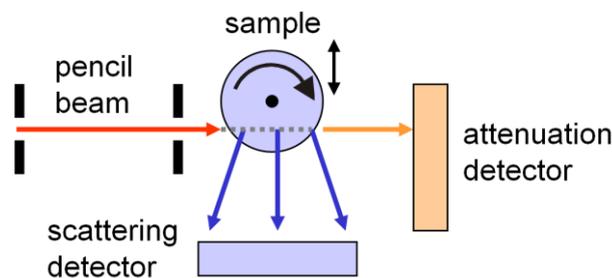


Fig. 4: Schematics of the twin interaction tomography set-up; vertical scans of sample through 40 μm pencil beam; simultaneous registration of attenuated direct beam intensity and 90° Compton scattered intensity by line scans at each projection angle.

4. Reconstruction strategy

For basic determination of the position dependent attenuation of the Compton scattering signals a model shape sample representing a homogeneous circular PE (polyethylene) cylinder is employed. Unlike the chord length distributions of cylinders in density profiles of absorption measurements the Compton scattering profiles are not symmetric as shown by Fig. 5 and are retained after 180° rotation. When the pencil beam penetrates the sample on the identical path AB inside the material the scattered photons are differently attenuated when leaving the sample at the opposite end after inversion of the direction (Fig. 5, right).

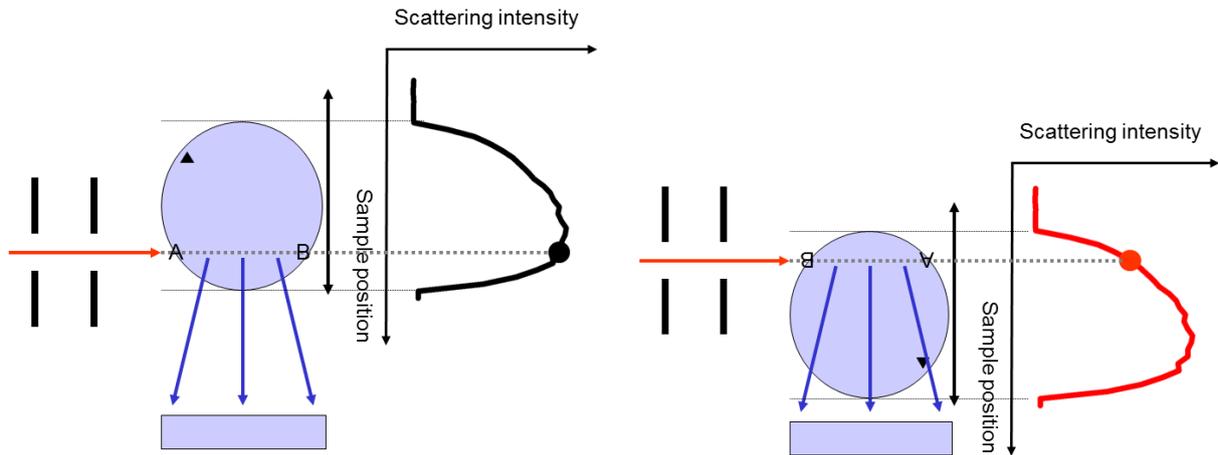


Fig. 5: Sampling profiles (Compton scattered intensity) of a cylindrical specimen rotated by 180°. While the pencil beam penetrates the sample on the identical path AB the scattered photons are differently attenuated when leaving the sample.

For correction of the asymmetric attenuation the corresponding profiles at projection angles φ_i and $(\varphi_i + 180^\circ)$ are averaged, resulting in shorter 180° sinograms of symmetric profiles as conducted in Fig. 6. Due to the absorptive modification of the Compton signals squared averaging is applied. The resulting reconstructions without and with correction are depicted at the bottom of the image.

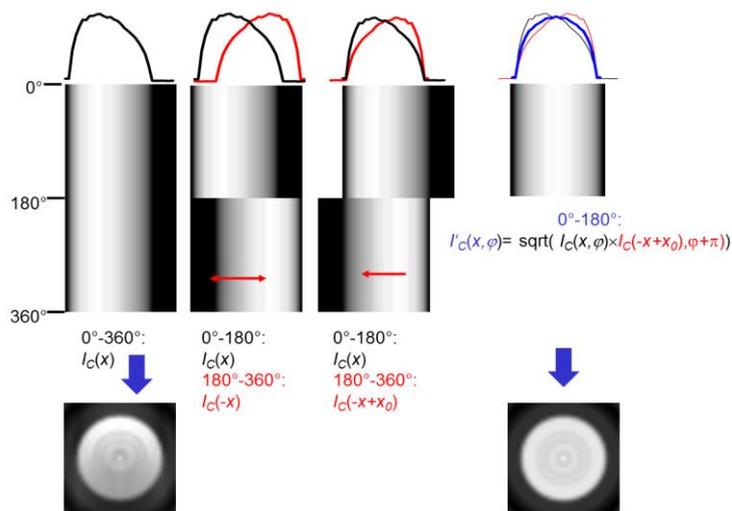


Fig. 6: Correction procedure of asymmetric attenuation of Compton scattering profiles in sinogram of cylinder by averaging profiles at projection angles φ_i and $(\varphi_i + 180^\circ)$ resulting in shorter 180° sinograms of symmetric profiles; resulting reconstructions at bottom.

5. Results – multi materials sample

For further investigation into the properties of Compton tomography by the twin X-ray interaction set-up a cylindrical multi material sample is measured. For current feasibility study a sparse number of 120 projections at 3° angular increments proved to be sufficient. The vertical 9 mm line scans were performed with $10\ \mu\text{m}$ increments. The individual materials arrangement is displayed in Fig. 7, left. The CT reconstruction of the related transmission signals at the attenuation detector is obtained by filtered back projection (Fig. 7, right). Although well defined monochromatic radiation and parallel beam projection nearly free of scattering is achieved, the very weak reconstruction contrast of the PE, wood and PA components demonstrates the weaknesses of conventional attenuation tomography even at moderate differences in materials attenuation.



Fig. 7: Sketch of the multi material sample, a PE tube filled with differently absorbing materials (left) and CT reconstruction of the transmission signals at the attenuation detector obtained by filtered back projection (3° angular increments).

The tomographic intensity sinograms I_A and I_C as obtained from the measurements of the multi material sample and some selected profiles are given by Fig 8. I_A is converted to extinction values $\mu \cdot d$ according to Lambert-Beer's law. I_C is treated according to the procedure of Fig. 6. The distorted I_C profiles at 75° and 255° (red and blue lines) compensate for a suitable I'_C profile (green line).

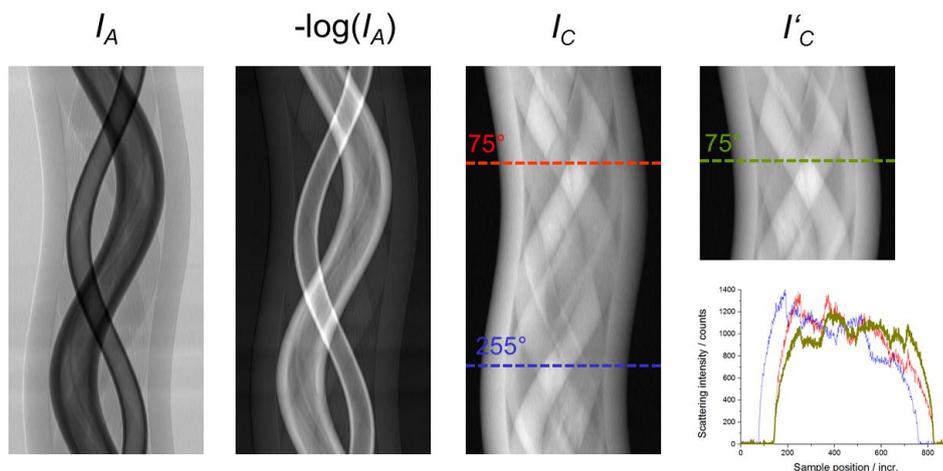


Fig. 8: Intensity sinograms I_A and I_C of 120 projection at 3° intervals as obtained from the measurement (see Fig. 5); I_A converted to $\mu \cdot d$ according to Lambert-Beer's law; selected Compton Scattering profiles of I_C treated according to the symmetry procedure of Fig. 6; distorted I_C profiles at 75° and 255° (red and blue lines) compensate to a suitable I'_C profile (green line).

For understanding the very different attenuation and scattering profiles of the sinograms a comparison of X-ray attenuation quantities for carbon, silicon and chlorine is made by Fig. 9. While the incoherent scattering is at roughly the same level for all three elements the

(photoelectric) true absorption differs tremendously. The coherent scattering is of minor interest in the present study. The vertical lines indicate the energy where the incoherent (Compton) scattering cross-section exceeds the absorption cross-section.

Extending the scope of material interactions with matter, neutron attenuation parameters are interesting for comparison, as neutron tomography is well known for its capability of contrasting almost all materials of different atomic numbers simultaneously within in a single reconstruction set. The different interactions of neutrons and X-rays with matter are sketched by Fig. 10 referring to absorption and scattering at electrons and nuclei. At right the very different attenuation parameters of both types of radiation versus atomic numbers are given.

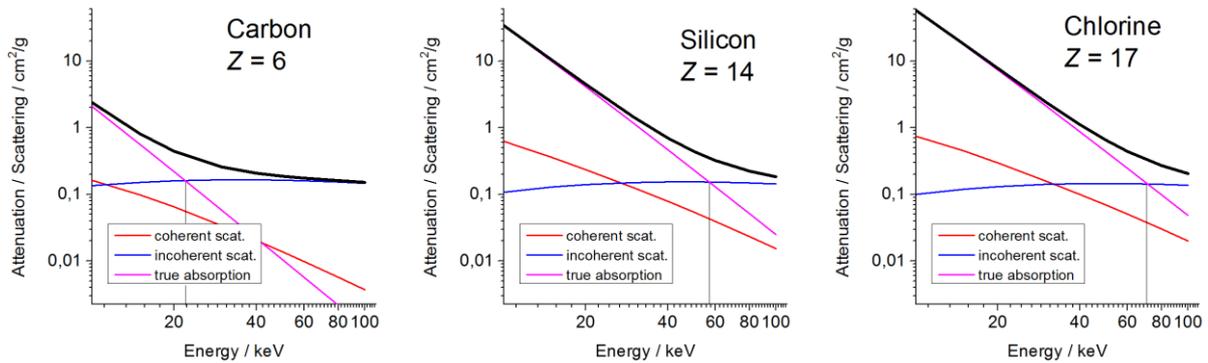


Fig. 9: Comparison of X-ray attenuation quantities for carbon, silicon and chlorine [31]; the incoherent scattering is at roughly the same level for all three elements the (photoelectric) true absorption differs tremendously. The coherent scattering is of minor interest in the present study. The vertical lines indicate the energy where the incoherent (Compton) scattering cross-section exceeds the absorption cross-section.

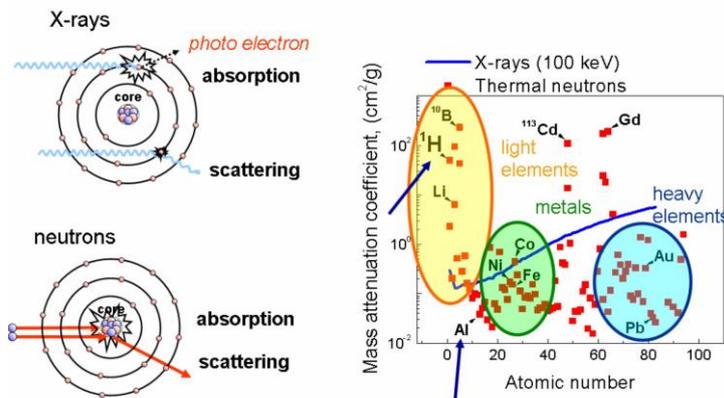


Fig. 10: Different interactions of neutrons and X-rays with matter; left: absorption and scattering at electrons and nuclei; right: very different attenuation of both types of radiation vs. atomic number.

Furthermore, a comparison of neutron and X-ray attenuation quantities for the elements contained in the test sample is made by Table 1.

Neutron tomography was performed at the Helmholtz-Zentrum Berlin für Materialien und Energie (Berlin, Germany) at the cold neutron imaging instrument CONRAD-2 [38]. It provides neutrons with wavelengths between 0.1 nm and 1.2 nm with a maximum at 0.25 nm. The detector system was based on a CCD camera with pixel size 30 μm . The number of the radiographic projections was 300 over 360°.

Tab. 1: Comparison of neutron and X-ray attenuation quantities for the elements contained in the test sample. (neutron data from [37] (1 barn = 10^{-28} m²), X-ray data from [31]).

| Element | Atomic number | Neutrons | | | 17.5 keV X-rays | |
|----------|---------------|---------------------------------------|--|---|---|--|
| | | Scattering length $b / 10^{-14}$ m | Incoherent scattering cross-section σ_{inc} / barn | Absorption cross-section (for $\lambda = 1.8$ Å) σ_{abs} / barn | Photo-absorption cross-section $\tau / \text{cm}^2/\text{g}$ | Inelastic cross-section $\sigma_{inc} / \text{cm}^2/\text{g}$ |
| Hydrogen | 1 | -0.37 | 79.7 | 0.33 | $4 \cdot 10^{-4}$ | 0.363 |
| Carbon | 6 | 0.66 | < 0.018 | 0.0033 | 0.32 | 0.155 |
| Nitrogen | 7 | 0.94 | 0.46 | 1.88 | 0.55 | 0.153 |
| Oxygen | 8 | 0.58 | < 0.015 | < 0.0002 | 0.91 | 0.150 |
| Silicon | 14 | 0.41 | < 0.017 | 0.16 | 6.0 | 0.135 |
| Chlorine | 17 | 0.96 | 5.9 | 33.6 | 10.8 | 0.125 |

The corrected Compton scattering sinogram (intensity I'_C in Fig. 8) is reconstructed by filtered back projection. For a final comparison of the properties of neutron and Compton tomography the reconstruction results obtained from neutron (left) and X-ray Compton (right) tomography are presented by Fig 11. Note that the glass tube is not visible in the neutron result.

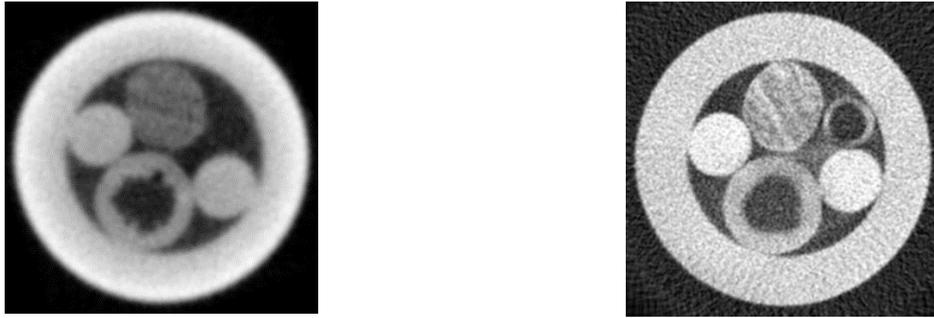


Fig. 11: Reconstruction results obtained from neutron (left) and X-ray Compton (right) tomography. Note that the glass tube is not visible in the neutron result.

6. Conclusion

Beyond former approaches of non-destructive Compton scattering inspection by direct localization of the interaction volume based on triangulation [1, 2] we have shown the feasibility of laboratory based Compton CT by twin interaction instrumentation applying 90° Compton scattering and conventional attenuation, simultaneously. In a first approach to reconstruct Compton scattering data by simple correction procedures very different components in a non-metallic composition of materials (atomic numbers up to 17) are highly contrasted at a similar level, which is a well-known (and also shown here) problem for classical attenuation.

Comparison to neutron data reveals similar contrast of the same sample, except for the glass tube, which is solely visible in Compton CT. Future developments regarding Compton CT could be successful in satisfying the increasing demands for imaging compositions of highly different materials. Furthermore, it is considered a promising approach to avoid refractive intensity distortions in high resolution measurements and could replace sophisticated neutron tomography in future.

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